Application/Control No.	Applicant(s)/Patent under Reexamination	
10/791,557	KANIZ ET AL.	
Examiner	Art Unit	
Jason K. Gee	2134	

	OFABOUED						
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Class	Subclass	Date	Examiner				
713	189	10/25/2007	JKG				
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INTERFERENCE SEARCHED					
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SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
EAST - US_PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT;	10/25/2007	JKG
Palm - Inventor Name Search	10/25/2007	JKG
IEEE - one chip	10/25/2007	JKG
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